

Search Notes



Application/Control No.

10/643,404

Examiner

Brian S. Kwon

Applicant(s)/Patent under Reexamination

TANAKA ET AL.

Art Unit

1614

SEARCHED

Class	Subclass	Date	Examiner
514	414	3/26/06	B
	165		
	457		
	523		
	56		
updated			

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
updated - smv. or rpl	3/26/06	B
- cutting date		
- Invention name search		